

**Supplementary material for “Mechanical Constraints Enhance Electrical Energy Densities
of Soft Dielectrics”**

Lin Zhang, Qiming Wang, and Xuanhe Zhao

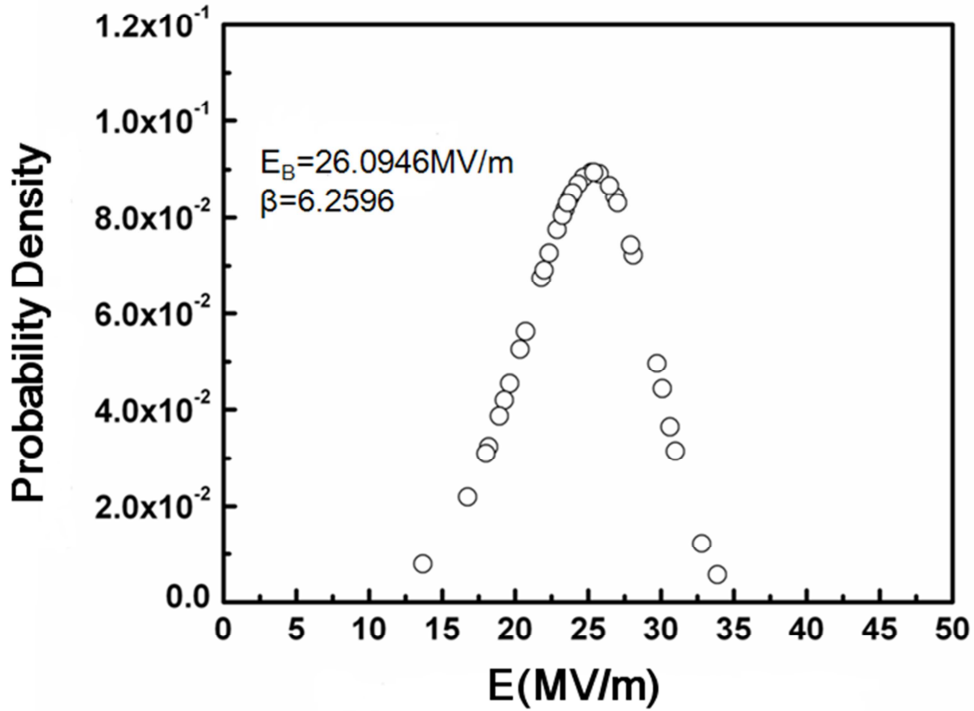


Figure S1. The characteristic breakdown fields of the dielectric films were evaluated by the two-parameter Weibull analysis,

$$P_f = 1 - \exp\left[-\left(E/E_B\right)^\beta\right] \quad (s1)$$

where P_f is the probability of the film to breakdown below an electric field E , E_B the characteristic breakdown field of the film, and β a shape parameter. We plot the probability density as a function of the measured breakdown field for two-side constraint Ecoflex with a defect. A characteristic breakdown field can be fitted to be 25.38MV/m.